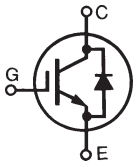
IXYS

Advance Technical Information

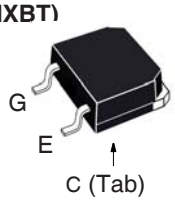
High Voltage, High Gain BIMOSFET™ Monolithic Bipolar MOS Transistor

IXBT22N300HV
IXBH22N300HV

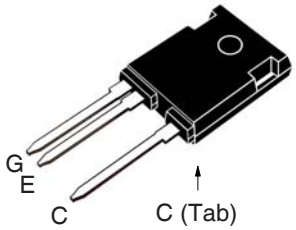
V_{CES} = 3000V
I_{C110} = 22A
$V_{CE(sat)} \leq$ 2.7V



TO-268HV (IXBT)



TO-247HV (IXBH)



G = Gate C = Collector
E = Emitter Tab = Collector

Symbol	Test Conditions	Maximum Ratings	
V_{CES}	T_J = 25°C to 150°C	3000	V
V_{CGR}	T_J = 25°C to 150°C, R_{GE} = 1MΩ	3000	V
V_{GES}	Continuous	± 20	V
V_{GEM}	Transient	± 30	V
I_{C25}	T_C = 25°C	60	A
I_{C110}	T_C = 110°C	22	A
I_{CM}	T_C = 25°C, 1ms	190	A
SSOA (RBSOA)	V_{GE} = 15V, T_{VJ} = 125°C, R_G = 15Ω Clamped Inductive Load	I_{CM} = 180 $V_{CES} \leq$ 1500	A V
T_{SC} (SCSOA)	V_{GE} = 15V, T_J = 125°C, R_G = 52Ω, V_{CE} = 1500V, Non-Repetitive	10	μs
P_C	T_C = 25°C	290	W
T_J		-55 ... +150	°C
T_{JM}		150	°C
T_{stg}		-55 ... +150	°C
T_L	Maximum Lead Temperature for Soldering	300	°C
T_{SOLD}	Plastic Body for 10s	260	°C
M_d	Mounting Torque (TO-247HV)	1.13/10	Nm/lb.in
Weight	TO-268HV TO-247HV	4 6	g g

Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
BV_{CES}	I_C = 250μA, V_{GE} = 0V	3000			V
$V_{GE(th)}$	I_C = 250μA, V_{CE} = V_{GE}	3.0		5.0	V
I_{CES}	V_{CE} = V_{CES}, V_{GE} = 0V			25	μA
	T_J = 125°C			1.5	mA
I_{GES}	V_{CE} = 0V, V_{GE} = ± 20V			±100	nA
$V_{CE(sat)}$	I_C = 22A, V_{GE} = 15V, Note 1		2.2	2.7	V
	T_J = 125°C		2.7		V

Features

- High Voltage Packages
- High Blocking Voltage
- High Peak Current Capability
- Low Saturation Voltage

Advantages

- Low Gate Drive Requirement
- High Power Density

Applications

- Switch-Mode and Resonant-Mode Power Supplies
- Uninterruptible Power Supplies (UPS)
- Laser Generators
- Capacitor Discharge Circuits
- AC Switches

IXYS

IXBT22N300HV
IXBH22N300HV

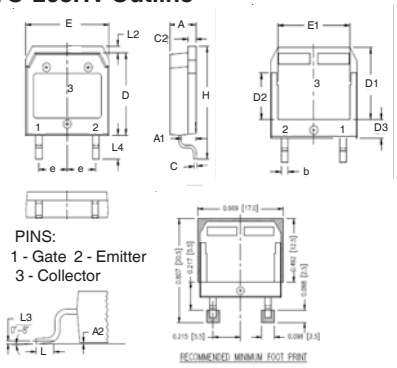
Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max.	
g_{fs}	I_C = 22A, V_{CE} = 10V, Note 1	13	22		S
C_{ies}	V_{CE} = 25V, V_{GE} = 0V, f = 1MHz		2200		pF
C_{oes}			85		pF
C_{res}			30		pF
$Q_{g(on)}$	I_C = 22A, V_{GE} = 15V, V_{CE} = 1500V		110		nC
Q_{ge}			13		nC
Q_{gc}			45		nC
$t_{d(on)}$	**Resistive Switching Times, T_J = 25°C**		46		ns
t_r	I_C = 22A, V_{GE} = 15V		360		ns
$t_{d(off)}$	V_{CE} = 960V, R_G = 15Ω		205		ns
t_f			1820		ns
$t_{d(on)}$	**Resistive Switching Times, T_J = 125°C**		43		ns
t_r	I_C = 22A, V_{GE} = 15V		700		ns
$t_{d(off)}$	V_{CE} = 960V, R_G = 15Ω		220		ns
t_f			1650		ns
R_{thJC}				0.43	°C/W
R_{thCS}	TO-247HV		0.21		°C/W

Reverse Diode

Symbol	Test Conditions (T_J = 25°C Unless Otherwise Specified)	Characteristic Values Min.	Typ.	Max	
V_F	I_F = 22A, V_{GE} = 0V, Note 1			2.7	V
t_{rr}	I_F = 11A, V_{GE} = 0V, $-di_F/dt$ = 100A/µs		1.4		µs
I_{RM}	V_R = 100V, V_{GE} = 0V		30		A
Q_{RM}			21		µC

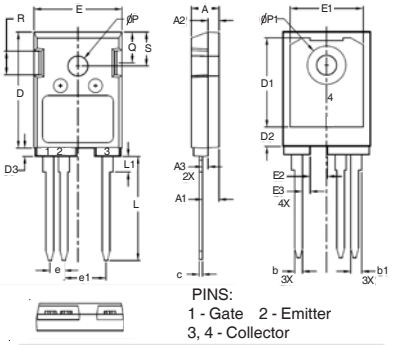
Note: 1. Pulse test, t ≤ 300µs, duty cycle, d ≤ 2%.

TO-268HV Outline



SYM	INCHES MIN	INCHES MAX	MILLIMETER MIN	MILLIMETER MAX
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
A2	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
C	.016	.026	0.40	0.65
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.465	.476	11.80	12.10
D2	.295	.307	7.50	7.80
D3	.114	.126	2.90	3.20
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215 BSC		5.45 BSC	
H	.736	.752	18.70	19.10
L	.067	.079	1.70	2.00
L2	.039	.045	1.00	1.15
L3	.010 BSC		0.25 BSC	
L4	.150	.161	3.80	4.10

TO-247HV Outline



SYM	INCHES MIN	INCHES MAX	MILLIMETERS MIN	MILLIMETERS MAX
A	.193	.201	4.90	5.10
A1	.114	.122	2.90	3.10
A2	.075	.083	1.90	2.10
A3	.035	.043	0.90	1.10
b	.053	.059	1.35	1.50
b1	.075	.083	1.90	2.10
c	.022	.030	0.55	0.75
D	.819	.843	20.80	21.40
D1	.638	.646	16.20	16.40
D2	.134	.146	3.40	3.70
D3	.055	.063	1.40	1.60
E	.622	.638	15.80	16.20
E1	.520	.528	13.20	13.40
E2	.118	.126	3.00	3.20
E3	.051	.059	1.30	1.50
e	.100 BSC		2.54 BSC	
e1	.300 BSC		7.62 BSC	
L	.732	.748	18.60	19.00
L1	.106	.118	2.70	3.00
øP	.138	.142	3.50	3.60
øP1	.272	.280	6.90	7.10
Q	.216	.224	5.50	5.70
R	.165	.169	4.20	4.30
S	.240	.248	6.10	6.30

ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

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IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,860,072 4,881,106 4,931,844 5,017,508 5,034,796 5,049,961 5,063,307 5,187,117 5,237,481 5,381,025 5,486,715 6,162,665 6,259,123 B1 6,306,728 B1 6,404,065 B1 6,534,343 6,583,505 6,683,344 6,710,405 B2 6,710,463 6,727,585 6,759,692 6,771,478 B2 7,005,734 B2 7,063,975 B2 7,071,537 7,157,338B2

Fig. 1. Output Characteristics @ T_J = 25ºC

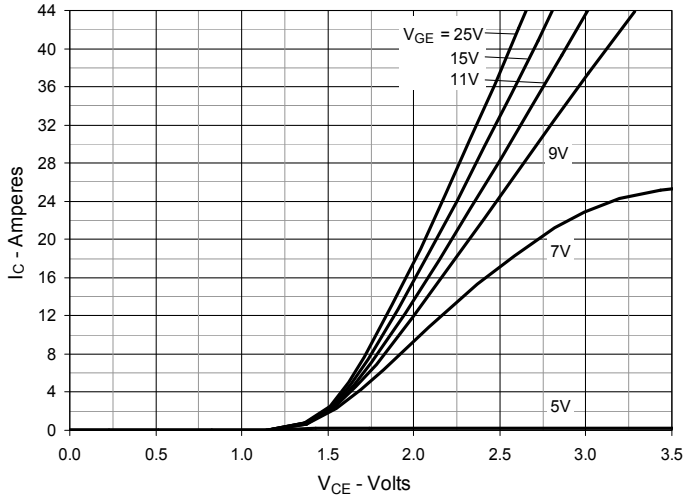

Fig. 2. Extended Output Characteristics @ T_J = 25ºC

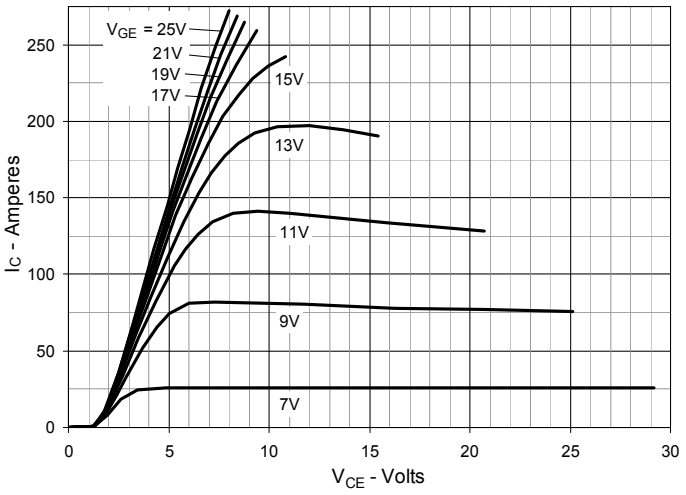

Fig. 3. Output Characteristics @ T_J = 125ºC

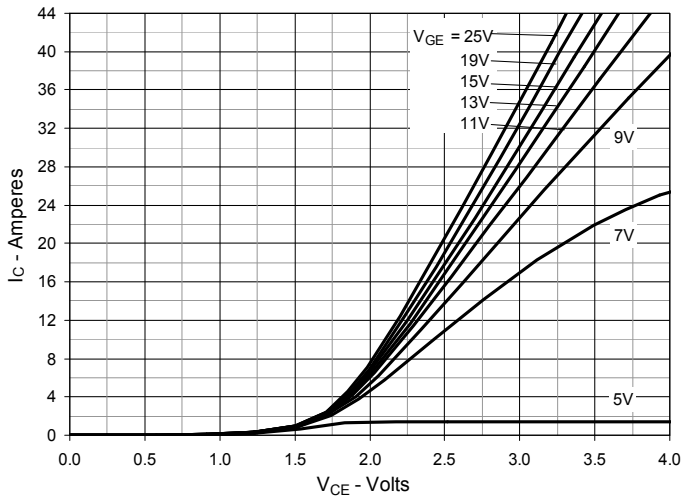

Fig. 4. Dependence of $V_{CE(sat)}$ on Junction Temperature

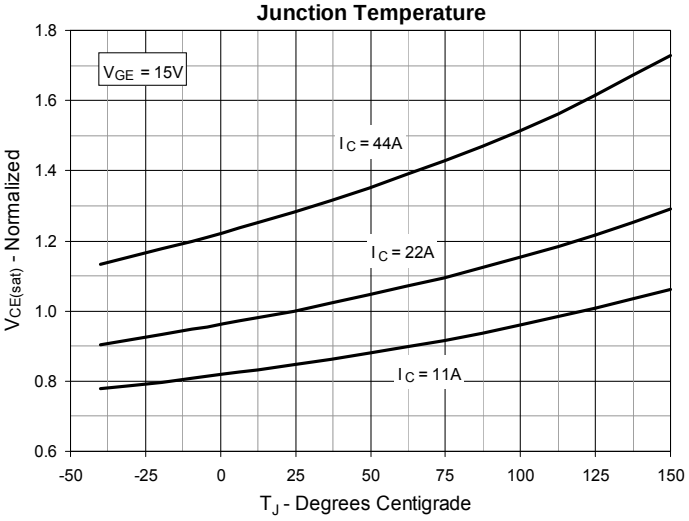

Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

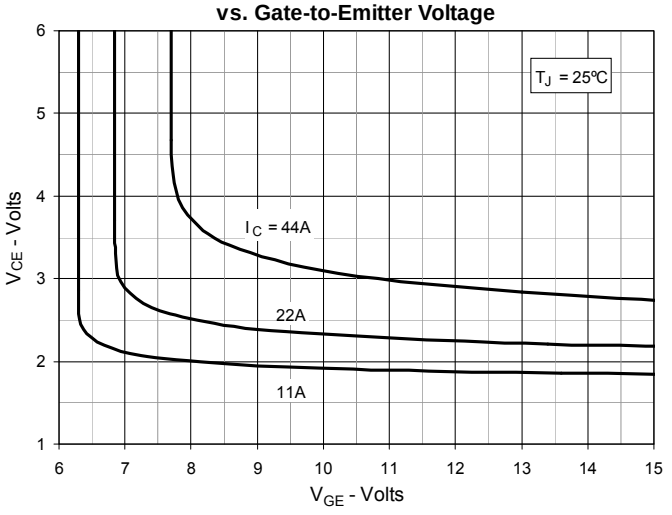

Fig. 6. Input Admittance

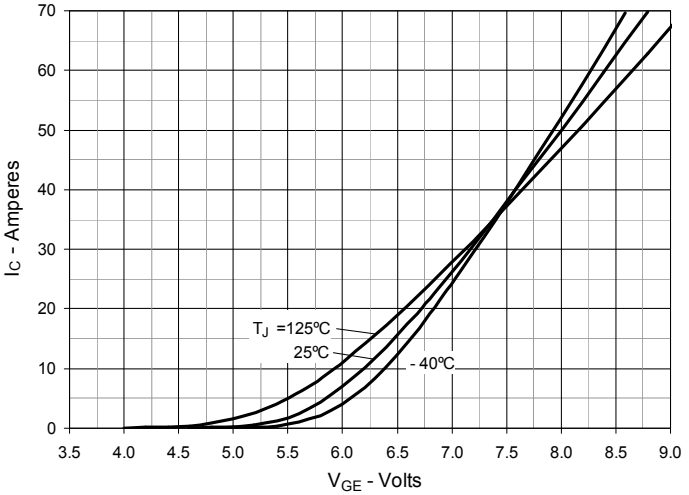

Fig. 7. Transconductance

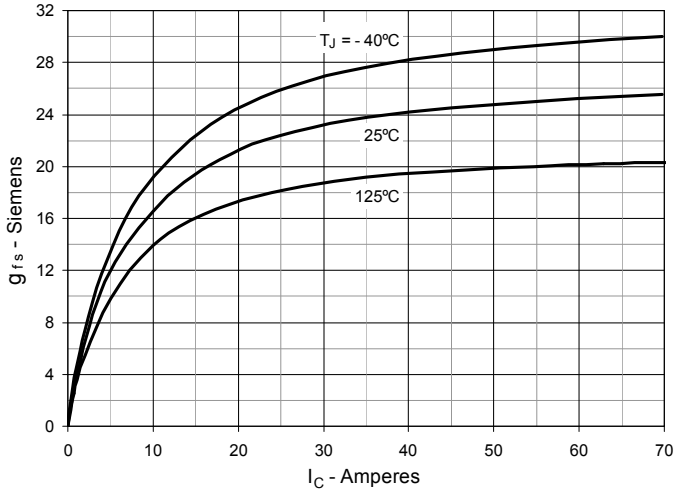

Fig. 8. Gate Charge

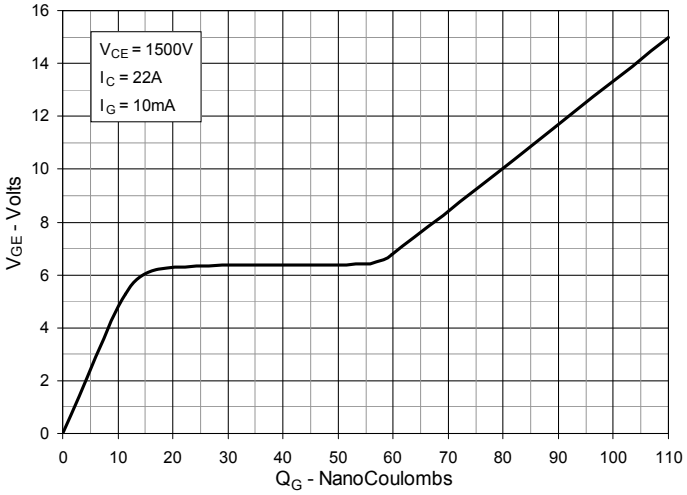

Fig. 9. Forward Voltage Drop of Intrinsic Diode

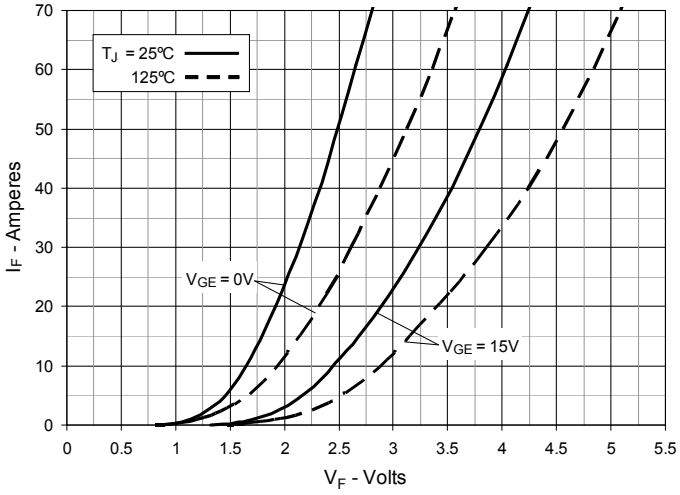

Fig. 10. Capacitance

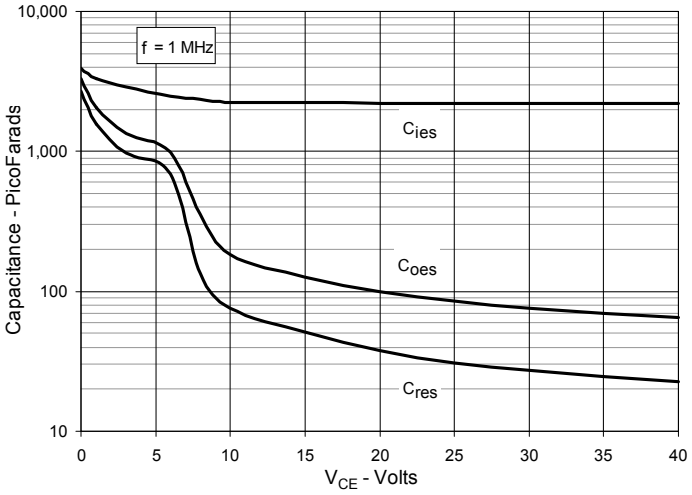

Fig. 11. Reverse-Bias Safe Operating Area

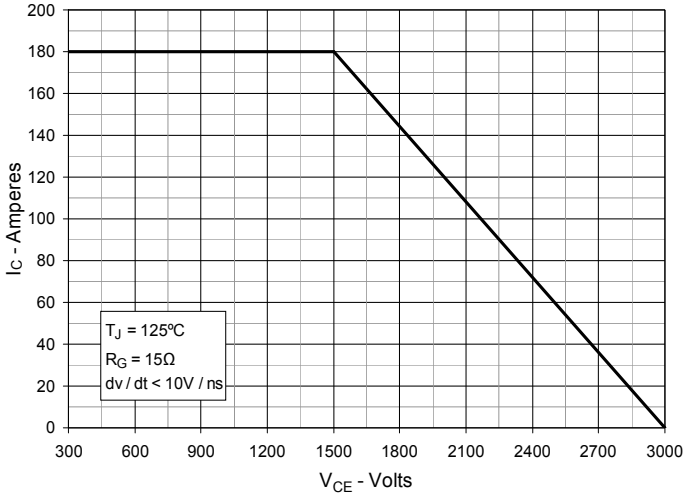

Fig. 12. Maximum Transient Thermal Impedance

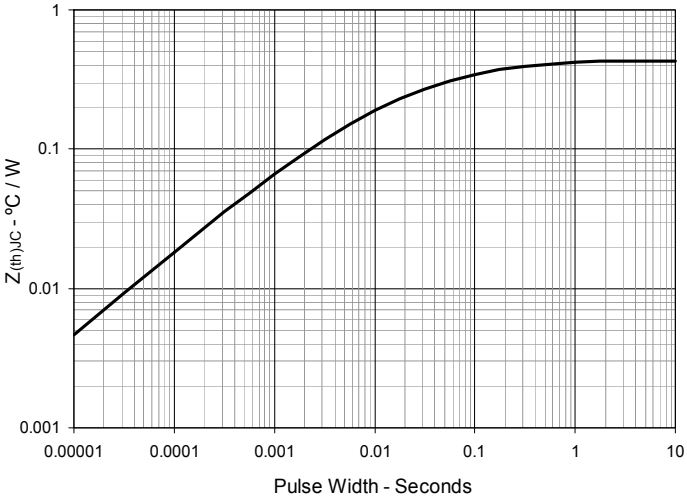

Fig. 13. Forward-Bias Safe Operating Area @ T_C = 25ºC

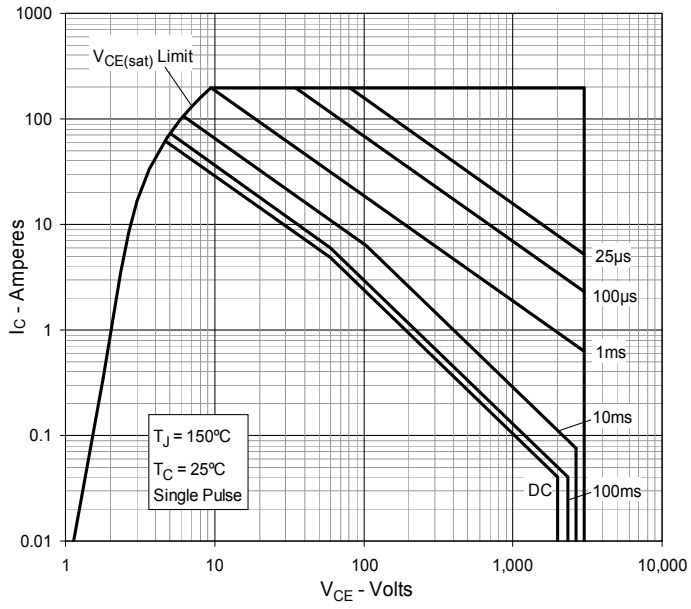

Fig. 14. Forward-Bias Safe Operating Area @ T_C = 75ºC